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(54) **Current-actuated-display backplane tester and method**

(57) A backplane (102) test system is provided that uses a pressed or deposited resistive film (120) and infrared (IR) imaging (160) to visualize and quantify the current drive of pixels. In one form, the system is used for measuring organic light-emitting-diode (OLED) backplanes or other current-actuated-display (CAD) backplanes.

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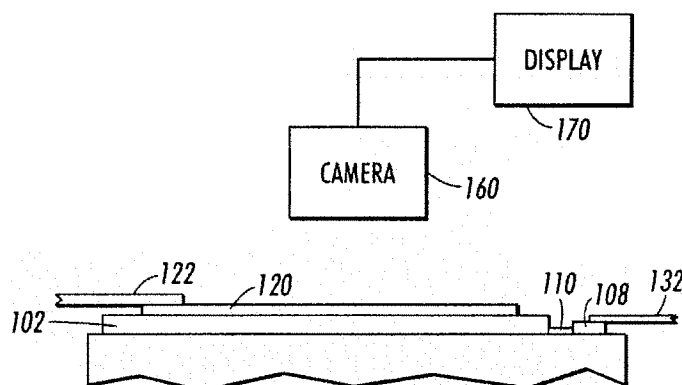


FIG. 2



EUROPEAN SEARCH REPORT

Application Number
EP 10 15 6695

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Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (IPC)
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			G09G
The present search report has been drawn up for all claims			
Place of search Munich		Date of completion of the search 25 February 2011	Examiner Demin, Stefan
CATEGORY OF CITED DOCUMENTS X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document		T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons & : member of the same patent family, corresponding document	

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**ANNEX TO THE EUROPEAN SEARCH REPORT
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EP 10 15 6695

This annex lists the patent family members relating to the patent documents cited in the above-mentioned European search report.
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专利名称(译)	电流驱动显示器背板测试器和方法		
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[标]申请(专利权)人(译)	帕洛阿尔托研究中心公司		
申请(专利权)人(译)	帕洛阿尔托研究中心INCORPORATED		
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其他公开文献	EP2230661A2		
外部链接	Espacenet		

摘要(译)

提供了一种底板 (102) 测试系统，其使用压制或沉积的电阻膜 (120) 和红外 (IR) 成像 (160) 来可视化和量化像素的电流驱动。在一种形式中，该系统用于测量有机发光二极管 (OLED) 背板或其他电流驱动显示器 (CAD) 背板。

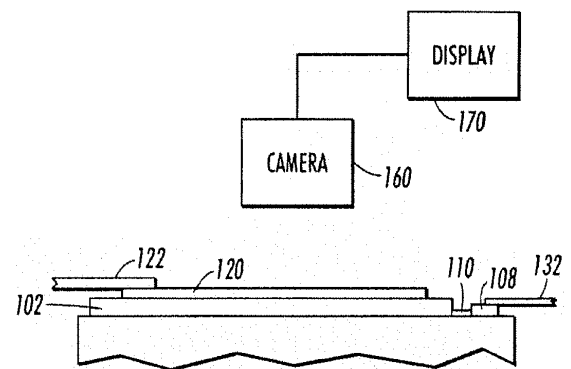


FIG. 2